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Supporting information for article:

High-resolution SAXS setup with tuneable resolution in direct and reciprocal space: a new tool to study ordered nanostructures

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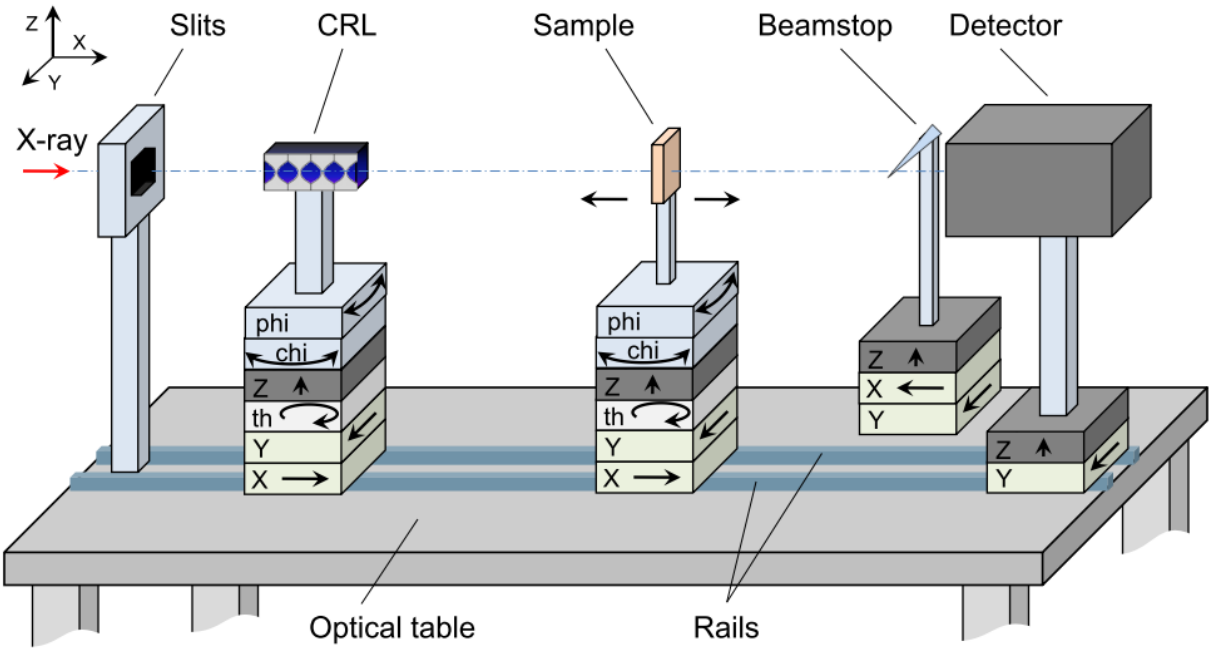

Figure S1 Block diagram of the compact SAXS setup with tuneable sample position.

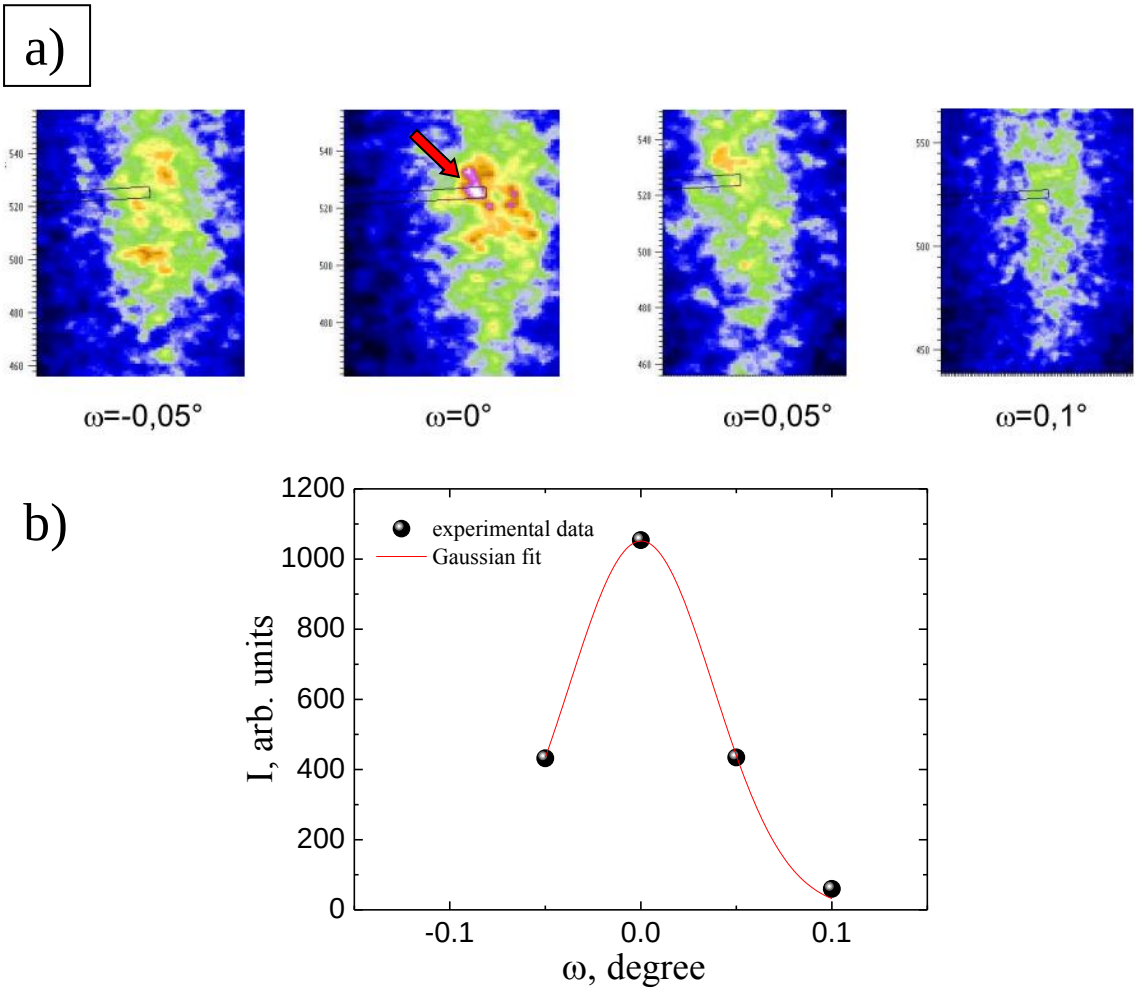

Figure S2 (a) Intensity distribution map near the 10 diffraction maximum. (b) Rocking curve of the diffraction point peak (2), shown in Fig. 3(a). The data were obtained at sample-detector distance L_{sd} = 216 mm (D = 31.5 μm), at φ = 3.3° and opening $\delta\varphi$ = 0.6°.